

## Special Issue

# Advancements in Optical Metrology and Imaging

### Message from the Guest Editors

Optical metrology and imaging are at the forefront of technological innovation, enabling precise measurements and high-resolution imaging across various fields. This Special Issue is dedicated to exploring research that advances the state of the art in these fields and will cater to contributions that address challenges in measurement accuracy, imaging resolution, and the integration of optical technologies with other disciplines. This Special Issue seeks to present research that will not only enhance our understanding of optical metrology but also drive innovation in applications critical to industries like manufacturing, healthcare, and train traffic. We are pleased to invite you to submit your recent work that spans from theoretical developments to practical applications related to optical metrology and imaging. Research areas may include (but are not limited to) the following: optical measurement, 3D/2D imaging, computational imaging, image processing, optical and visual inspection for surface defects, and deep learning and machine learning applications related to optical imaging techniques. We look forward to receiving your contributions.

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### Guest Editors

Dr. Yingying Wan

Dr. Ji Tan

Dr. Gaoxu Wu

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### Deadline for manuscript submissions

31 August 2025



## Photonics

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## About the Journal

### Message from the Editor-in-Chief

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#### Editor-in-Chief

Prof. Dr. Nelson Tansu  
School of Electrical and Electronic Engineering (EEE), The University of  
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indexed within Scopus, SCIE (Web of Science), Inspec,  
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##### Rapid Publication:

manuscripts are peer-reviewed and a first decision is  
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